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*Examiner		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date I Appropriate	
Y //	A1	6,534,395	03/18/03	Werkhoven, et al.	43	£27	03/ 01	
119	A2	6,482,740	11/19/02	Soininen, et al.	4:	É	05/ 01	
_	A3	6,482,733	11/19/02	Raaijmakers, et al.	4	e	04/2 01	
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·	A5	6,475,910	11/05/02	Sneh	4	6	09/2 00	
45	A6	6,475,276	11/05/02	Elers, et al.	1	8	10/	
	A7	6,468,924	10/22/02	Lee, et al.	4		05/001	
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	B2	02/067319	08/29/02	wo	131			
	B3	2001-111000	04/20/01	JP	14.1			
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Towns and the same of the same	A8	6,305,314 10/31/01		Sneh, et al.	1	3 7:	R	12/1 99			
	A9	6,284,646	09/04/01	Leem	4	6.	9	08/1 98			
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17	A2	2002/0090829	07/11/02	Sandhu, et al.	43	3	76	01/31 02	
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• \	A5	2002/0061612	05/23/02	Sandhu, et al.	43	3	15	01/14)2	
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n	A11	2002/0019121	02/14/02	Pyo	4	8	618	06/20/01	
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	A13	2002/0004293	01/10/02	Soininen, et al.	43	2	58	05/15/01	
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47	A1	4,058,430	11/15/7	7	Suntola et al.			6	11/2 5
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	A44	4,859,625	8/22/89		Nishizawa et al.		4	81	11/2/87
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	A21	4,951,601	8/28/90		Maydan, et al.		1	71	6/2 9
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	A37	5,234,561	8/10/93	Randhawa et al	. 20	2.38	8/2 38
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	A58	5,374,570	12/20/94	Nasu et al.	4	4.	8/1, 93
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	A71	5,503,875	4/2/96	Imai et al.	427	2 .3	3/1794
	A72	5,521,126	5/28/96	Okamura et al.	437	2	6/223)4
	A73	5,527,733	6/18/96	Nishizawa et al	. 43		2/13/04
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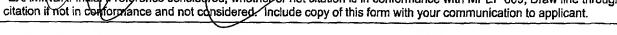


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	B19	62-171999	7/28/87	JP	C: 3	29		17
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1	B21	63-062313	3/18/88	JP	H.	2: 03		+=
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